

**EH1125TTS-49.152M**
[Click part number to visit Part Number Details page](#)
**REGULATORY COMPLIANCE** (Data Sheet downloaded on Feb 9, 2018)
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**ITEM DESCRIPTION**

Quartz Crystal Clock Oscillators XO (SPXO) HCMOS/TTL (CMOS) 5.0Vdc 14 Pin DIP Metal Thru-Hole 49.152MHz  $\pm 25$ ppm 0°C to +70°C

**ELECTRICAL SPECIFICATIONS**

<b>Nominal Frequency</b>	49.152MHz
<b>Frequency Tolerance/Stability</b>	$\pm 25$ ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operation Temperature Range, Supply Voltage Change, Output Load Change, 1st Year Aging at 25°C, Shock, and Vibration)
<b>Aging at 25°C</b>	$\pm 5$ ppm/year Maximum
<b>Operating Temperature Range</b>	0°C to +70°C
<b>Supply Voltage</b>	5.0Vdc $\pm 10\%$
<b>Input Current</b>	50mA Maximum (No Load)
<b>Output Voltage Logic High (Voh)</b>	2.4Vdc Minimum with TTL Load, Vdd-0.4Vdc Minimum with HCMOS Load (IOH = -16mA)
<b>Output Voltage Logic Low (Vol)</b>	0.4Vdc Maximum with TTL Load, 0.5Vdc Maximum with HCMOS Load (IOL = +16mA)
<b>Rise/Fall Time</b>	6nSec Maximum (Measured at 0.8Vdc to 2.0Vdc with TTL Load, 20% to 80% of waveform with HCMOS Load)
<b>Duty Cycle</b>	50 $\pm 5$ (%) (Measured at 50% of waveform with TTL Load or with HCMOS Load)
<b>Load Drive Capability</b>	10TTL Load or 50pF HCMOS Load Maximum
<b>Output Logic Type</b>	CMOS
<b>Pin 1 Connection</b>	Tri-State (High Impedance)
<b>Tri-State Input Voltage (Vih and Vil)</b>	+2.2Vdc Minimum to enable output, +0.8Vdc Maximum to disable output (High Impedance), No Connect to enable output.
<b>Absolute Clock Jitter</b>	$\pm 250$ pSec Maximum, $\pm 100$ pSec Typical
<b>One Sigma Clock Period Jitter</b>	$\pm 50$ pSec Maximum, $\pm 30$ pSec Typical
<b>Start Up Time</b>	10mSec Maximum
<b>Storage Temperature Range</b>	-55°C to +125°C

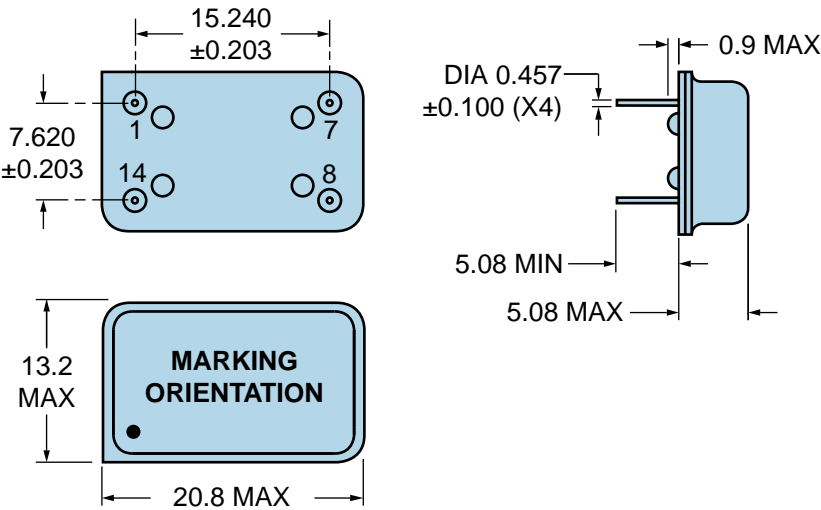
**ENVIRONMENTAL & MECHANICAL SPECIFICATIONS**

<b>Fine Leak Test</b>	MIL-STD-883, Method 1014, Condition A
<b>Gross Leak Test</b>	MIL-STD-883, Method 1014, Condition C
<b>Lead Integrity</b>	MIL-STD-883, Method 2004
<b>Mechanical Shock</b>	MIL-STD-202, Method 213, Condition C
<b>Resistance to Soldering Heat</b>	MIL-STD-202, Method 210
<b>Resistance to Solvents</b>	MIL-STD-202, Method 215
<b>Solderability</b>	MIL-STD-883, Method 2003
<b>Temperature Cycling</b>	MIL-STD-883, Method 1010
<b>Vibration</b>	MIL-STD-883, Method 2007, Condition A

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MECHANICAL DIMENSIONS (all dimensions in millimeters)



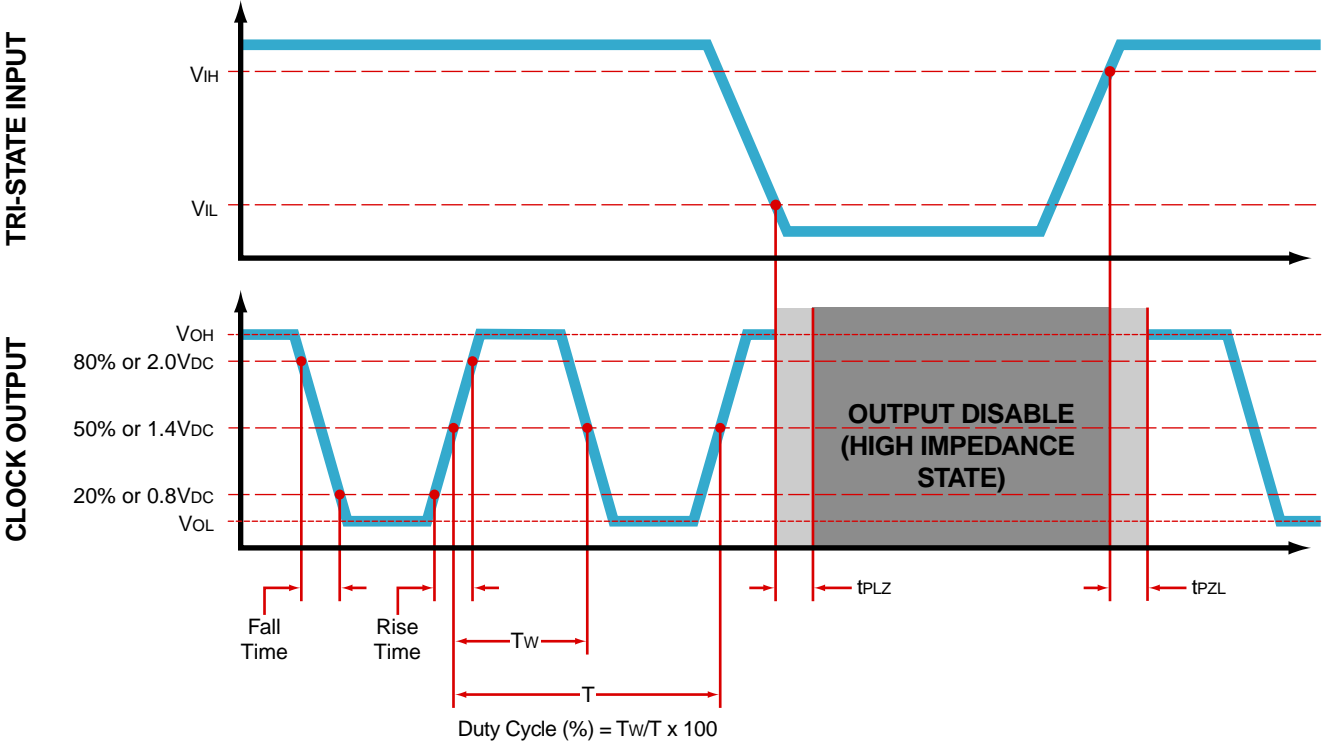
PIN	CONNECTION
1	Tri-State (High Impedance)
7	Ground/Case Ground
8	Output
14	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	EH11TS EH11=Product Series
3	49.152M
4	XXYYZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

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OUTPUT WAVEFORM & TIMING DIAGRAM



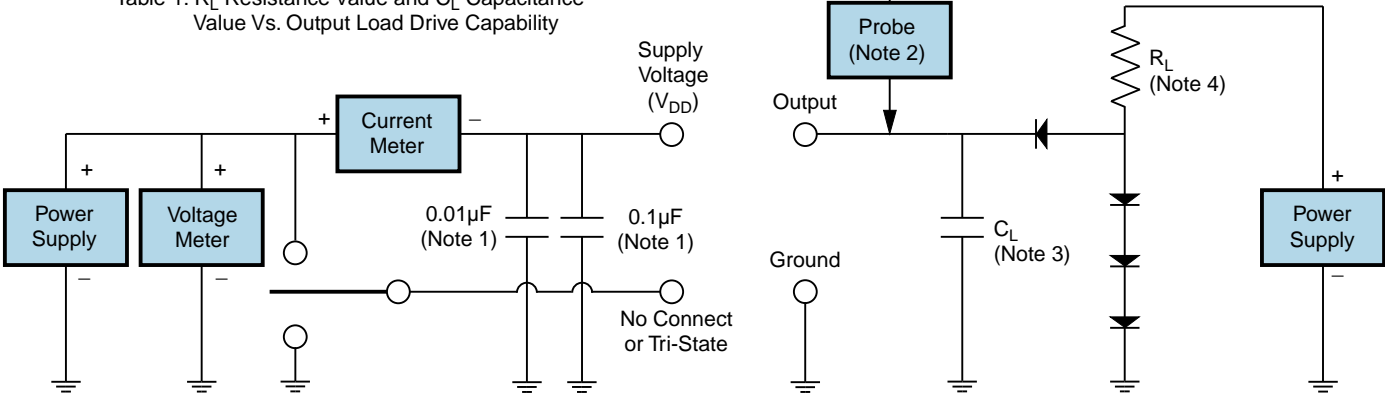
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Test Circuit for TTL Output

Output Load Drive Capability	R <sub>L</sub> Value (Ohms)	C <sub>L</sub> Value (pF)
10TTL	390	15
5TTL	780	15
2TTL	1100	6
10LSTTL	2000	15
1TTL	2200	3

Table 1: R<sub>L</sub> Resistance Value and C<sub>L</sub> Capacitance Value Vs. Output Load Drive Capability

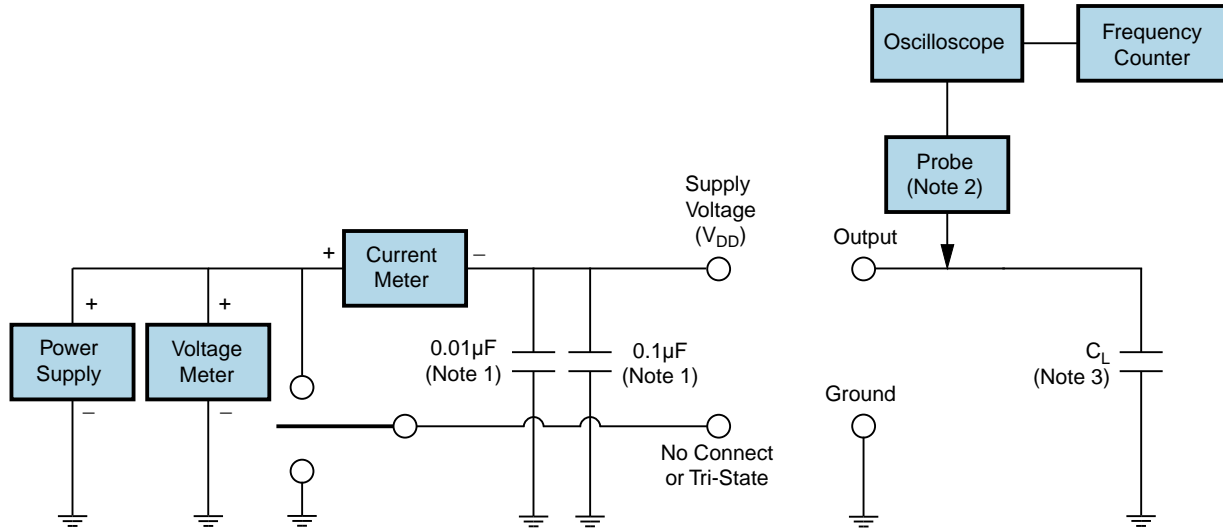


- Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value C<sub>L</sub> includes sum of all probe and fixture capacitance.
- Note 4: Resistance value R<sub>L</sub> is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.
- Note 5: All diodes are MMBD7000, MMBD914, or equivalent.

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## Test Circuit for CMOS Output



Note 1: An external  $0.1\mu\text{F}$  low frequency tantalum bypass capacitor in parallel with a  $0.01\mu\text{F}$  high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.

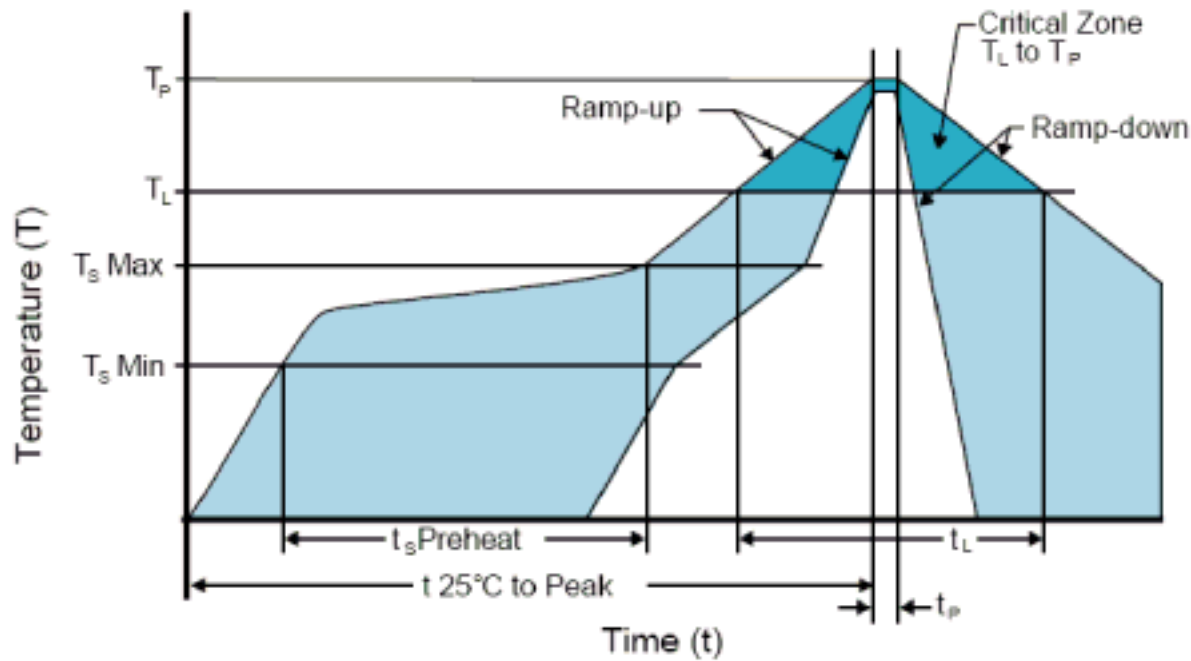
Note 2: A low capacitance ( $<12\text{pF}$ ), 10X attenuation factor, high impedance ( $>10\text{Mohms}$ ), and high bandwidth ( $>300\text{MHz}$ ) passive probe is recommended.

Note 3: Capacitance value  $C_L$  includes sum of all probe and fixture capacitance.

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Recommended Solder Reflow Methods



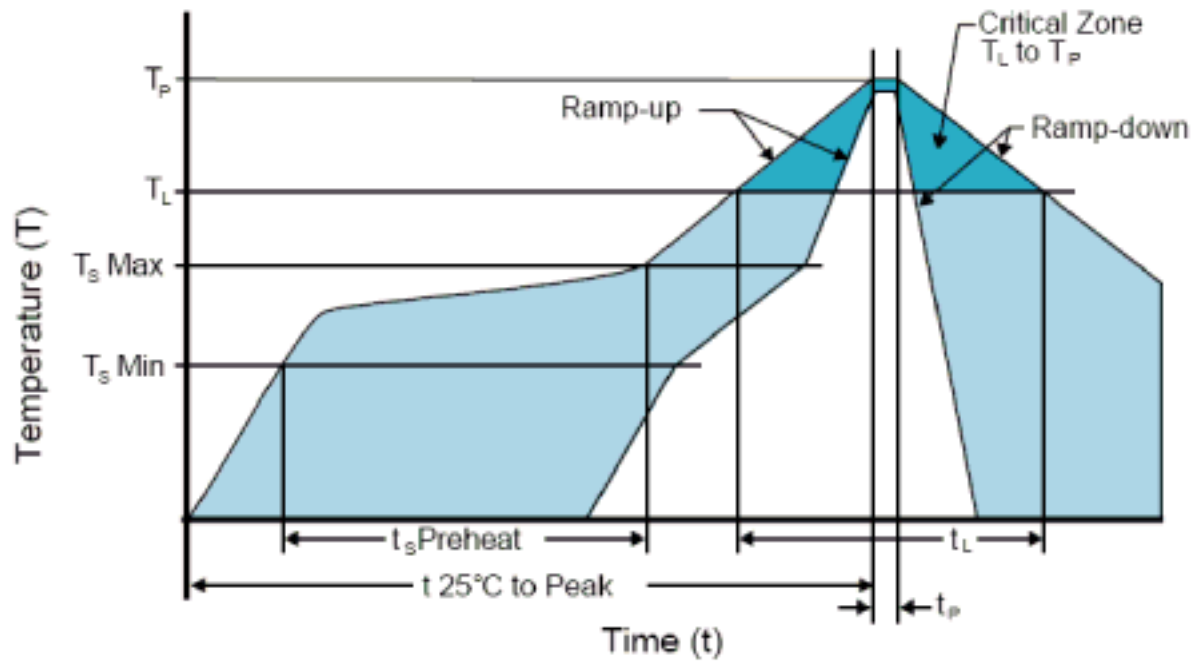
High Temperature Solder Bath (Wave Solder)

Ts MAX to TL (Ramp-up Rate)	3°C/Second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	150°C
- Temperature Typical (Ts TYP)	175°C
- Temperature Maximum (Ts MAX)	200°C
- Time (ts MIN)	60 - 180 Seconds
Ramp-up Rate (TL to TP)	3°C/Second Maximum
Time Maintained Above:	
- Temperature (TL)	217°C
- Time (tL)	60 - 150 Seconds
Peak Temperature (TP)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (TP Target)	250°C +0/-5°C
Time within 5°C of actual peak (tp)	20 - 40 Seconds
Ramp-down Rate	6°C/Second Maximum
Time 25°C to Peak Temperature (t)	8 Minutes Maximum
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.

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Recommended Solder Reflow Methods



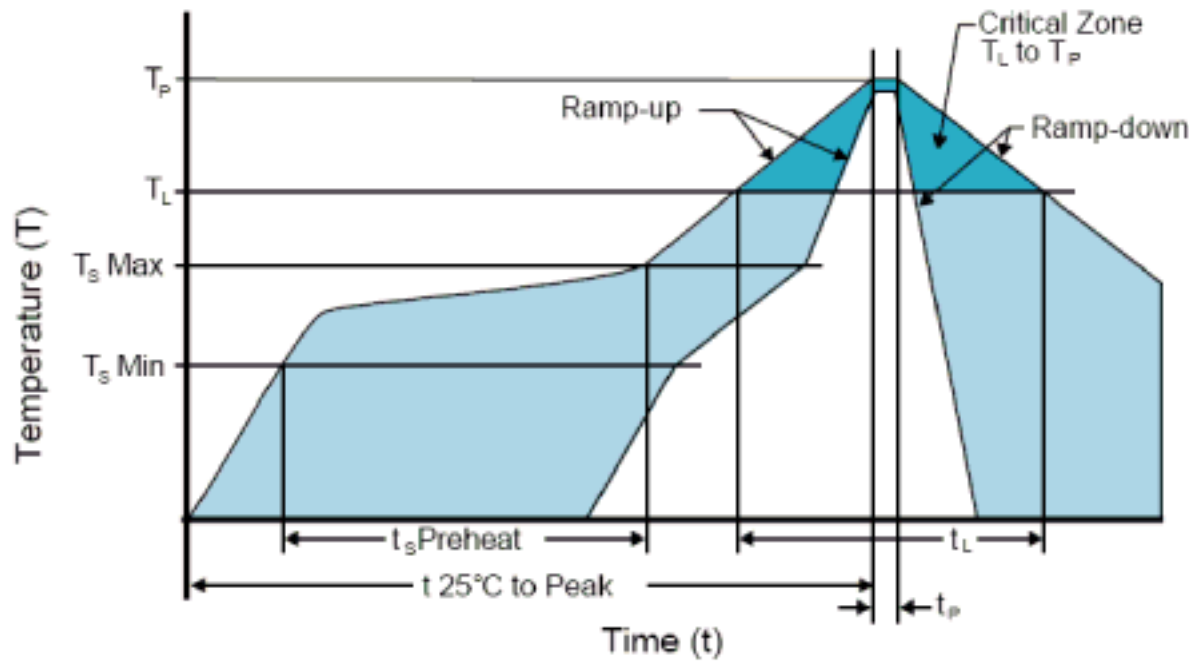
Low Temperature Infrared/Convection 185°C

<b>Ts MAX to TL (Ramp-up Rate)</b>		5°C/Second Maximum
<b>Preheat</b>		
- Temperature Minimum (Ts MIN)	N/A	
- Temperature Typical (Ts TYP)	150°C	
- Temperature Maximum (Ts MAX)	N/A	
- Time (ts MIN)	60 - 120 Seconds	
<b>Ramp-up Rate (TL to TP)</b>		5°C/Second Maximum
<b>Time Maintained Above:</b>		
- Temperature (TL)	150°C	
- Time (tL)	200 Seconds Maximum	
<b>Peak Temperature (TP)</b>		185°C Maximum
<b>Target Peak Temperature (TP Target)</b>		185°C Maximum 2 Times
<b>Time within 5°C of actual peak (tp)</b>		10 Seconds Maximum 2 Times
<b>Ramp-down Rate</b>		5°C/Second Maximum
<b>Time 25°C to Peak Temperature (t)</b>		N/A
<b>Moisture Sensitivity Level</b>		Level 1
<b>Additional Notes</b>		Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option.

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Recommended Solder Reflow Methods



Low Temperature Solder Bath (Wave Solder)

Ts MAX to TL (Ramp-up Rate)	5°C/Second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	N/A
- Temperature Typical (Ts TYP)	150°C
- Temperature Maximum (Ts MAX)	N/A
- Time (ts MIN)	30 - 60 Seconds
Ramp-up Rate (TL to TP)	5°C/Second Maximum
Time Maintained Above:	
- Temperature (TL)	150°C
- Time (tL)	200 Seconds Maximum
Peak Temperature (TP)	245°C Maximum
Target Peak Temperature (TP Target)	245°C Maximum 1 Time / 235°C Maximum 2 Times
Time within 5°C of actual peak (tP)	5 Seconds Maximum 1 Time / 15 Seconds Maximum 2 Times
Ramp-down Rate	5°C/Second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1
Additional Notes	Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option.

Low Temperature Manual Soldering

185°C Maximum for 10 Seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

High Temperature Manual Soldering

260°C Maximum for 5 Seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)